



## **Call for Participation for Special session Blockchain and IA Integration in Embedded Systems**



It is our pleasure to invite you to participate in the IEEE International Conference on Design, Test and Technology of Integrated Systems (DTTIS 2026).

DTTIS'26 is organized by National Engineer School of Sfax in collaboration with the IEEE Tunisia section and co-sponsored by the IEEE Computer society TTTC. The event is going to be organized on November 4 - 6, 2026.

IEEE DTTIS'26 represents a scientific and technological event dedicated to integrated electronic systems which reach the nanoscale era. The interests of the conference cover all the aspects from the design to the test of micro and nano systems. IEEE DTTIS'26 is an important meeting where well-known researchers from universities and companies will present the latest innovations in the field of micro and nano electronics.

It will also provide engineers with an opportunity to interact and share their experiences in industry and technology applications.

### **Special Session Topics :**

Embedded systems are a category of electronic systems dedicated for a specific task or domain. They are used in various domains such as consumer electronics, automobiles, medical devices, mobile robots and industrial automation. With the rapid emergence of complex applications such as artificial intelligence and blockchains techniques, the integration of these advanced algorithms into embedded systems has become increasingly important and challenging. Indeed, as these applications are both data and computing intensive, their execution on relatively low complex architecture puts stringent constraints on both applications and architectures.

The scope of this special session includes, but is not limited to the following topics:

- FPGA-based AI accelerators
- AI applications for E-health, mobile applications and E-learning
- Cases study of Edge AI GPU Computing
- Blockchain applications for embedded systems
- On-chain // off-chain embedded implementation
- AI-based hardware reliability

The conference paper should be prepared according to the IEEE standard format. The manuscript should be written in English using a two-column layout on A4 or Letter-size paper. Authors are required to use the official IEEE conference template available in Microsoft Word or LaTeX formats.

IEEE Templates : <https://www.ieee.org/conferences/publishing/templates>

**Papers should be sent to one of the three organizers:**



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